

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

General Description

The MAX5318 is a high-accuracy, 18-bit, serial SPI input, buffered voltage output digital-to-analog converter (DAC) in a 4.4mm x 7.8mm, 24-lead TSSOP package. The device features ±2 LSB INL (max) accuracy and a ±1 LSB DNL (max) accuracy over the full temperature range

The DAC voltage output is buffered resulting in a fast settling time of $3\mu s$ and a low offset and gain drift of $\pm 0.5 ppm/^{\circ}C$ of FSR (typ). The force-sense output (OUT) maintains accuracy while driving loads with long lead lengths. Additionally, a separate AVSS supply, allows the output amplifier to go to 0V (GND) while maintaining full linearity performance.

The MAX5318 includes user-programmable digital gain and offset correction to enable easy system calibration.

At power-up, the device resets its outputs to zero or midscale. The wide 2.7V to 5.5V supply voltage range and integrated low-drift, low-noise reference buffer amplifier make for ease of use.

The MAX5318 features a 50MHz 3-wire SPI interface. The MAX5318 is available in a 24-lead TSSOP package and operates over the -40 $^{\circ}$ C to +105 $^{\circ}$ C temperature range.

Benefits and Features

- ♦ Ideal for ATE and High-Precision Instruments
 - ♦ INL Accuracy Guaranteed with ±2 LSB (Max) Over Temperature
- ♦ Fast Settling Time (3µs) with 10kΩ || 100pF Load
- ♦ Safe Power-Up-Reset to Zero or Midscale DAC Output (Pin-Selectable)
 - Predetermined Output Device State in Power-Up and Reset in System Design
- Negative Supply (AVSS) Option Allows Full INL and DNL Performance to 0V
- ♦ SPI Interface Compatible with 1.8V to 5.5V Logic
- ♦ High Integration Reduces Development Time and PCB Area
 - Buffered Voltage Output Directly Drives
 2kΩ Load Rail-to-Rail
 - ♦ Integrated Reference Buffer
 - ♦ No External Amplifiers Required
- ♦ Small 4.4mm x 7.8mm, 24-Pin TSSOP Package

<u>Ordering Information</u> and <u>Typical Operating Circuit</u> appear at end of data sheet.

Applications

Test and Measurement Equipment Automatic Test Equipment Gain and Offset Adjustment Data-Acquisition Systems Process Control and

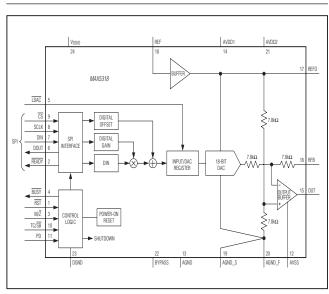
Servo Loops

of -40°C to +105°C.

Programmable Voltage and Current Sources Automatic Tuning and Calibration Communication Systems Medical Imaging

For related parts and recommended products to use with this part, refer to www.maximintegrated.com/MAX5318.related.

Functional Diagram



For pricing, delivery, and ordering information, please contact Maxim Direct at 1-888-629-4642, or visit Maxim's website at www.maximintegrated.com.

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ABSOLUTE MAXIMUM RATINGS

AGND to DGND0.3V to +0.3V	REF to AGND0.3V to the lower of VAVDD and +6V
AGND_F, AGND_S to AGND0.3V to +0.3V	SCLK, DIN, CS, BUSY, LDAC, READY,
AGND_F, AGND_S to DGND0.3V to +0.3V	M/\overline{Z} , TC/\overline{SB} , \overline{RST} , PD, DOUT to DGND0.3V to the lower of
AVDD to AGND0.3V to +6V	$(V_{DDIO} + 0.3V)$ and +6V
AVDD to REF0.3V to +6V	Continuous Power Dissipation (T _A = +70°C)
AVSS to AGND2V to +0.3V	TSSOP (derate 13.9mW/°C above +70°C)1111.1mW
V _{DDIO} to DGND0.3V to +6V	Operating Temperature Range40°C to +105°C
BYPASS to DGND0.3V to the lower of	Maximum Junction Temperature+150°C
$(V_{AVDD} \text{ or } V_{DDIO} + 0.3V) \text{ and } +4.5V$	Storage Temperature Range65°C to +150°C
OUT, REFO, RFB to AGND0.3V to the lower of	Lead Temperature (soldering, 10s)+300°C
$(V_{AVDD} + 0.3V)$ and +6V	Soldering Temperature (reflow)+260°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

PACKAGE THERMAL CHARACTERISTICS (Note 1)

TSSOP

Junction-to-Case Thermal Resistance (θ_{JA}).......13°C/W Junction-to-Ambient Thermal Resistance (θ_{JA}).......72°C/W

Note 1: Package thermal resistances were obtained using the method described in JEDEC specification JESD51-7, using a four-layer board. For detailed information on package thermal considerations, refer to **www.maximintegrated.com/thermal-tutorial**.

ELECTRICAL CHARACTERISTICS

 $(V_{AVDD} = V_{DDIO} = \textbf{4.5V to 5.5V}, \ V_{AVSS} = -1.25 V, \ V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0 V, \ V_{REF} = 4.096 V, \ TC/\overline{SB} = PD = \overline{LDAC} = M/\overline{Z} = DGND, \ \overline{RST} = V_{DDIO}, \ C_{REFO} = 100 pF, \ C_L = 100 pF, \ R_L = 10 k\Omega, \ C_{BYPASS} = 1 \mu F, \ T_A = -40 ^{\circ}C \ to +105 ^{\circ}C, \ unless otherwise noted. Typical values are at T_A = +25 ^{\circ}C.) (GAIN = 0x3FFFF and OFFSET = 0x00000.) (Note 2)$

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
STATIC PERFORMANCE						
Resolution	N		18			Bits
Integral Nonlinearity (Note 3)	INII	DIN = 0x00000 to 0x3FFFF (binary mode), DIN = 0x20000 to 0x1FFFF (two's complement mode)	-2	.0.5	. 0	. 00
	INL	DIN = 0x01900 to 0x3FFFF (binary mode), DIN = 0x21900 to 0x1FFFF (two's complement mode), V _{AVSS} = 0V	-2	±0.5	+2	LSB
Differential Nonlinearity (Note 3)	DNL		-1	±0.275	+1	LSB
Zero Code Error	OE	DIN = 0, $T_A = +25^{\circ}C$	-48	±4	+48	LSB
Zero Gode Error		DIN = 0, $T_A = -40^{\circ}\text{C}$ to $+105^{\circ}\text{C}$		±14		LOD
Zero Code Error Drift (Note 4)		DIN = 0	-1.6	±0.10	+1.6	ppm/°C
Gain Error	GE	$T_A = +25^{\circ}C$	-16	±1	+16	LSB
Gain Endi	GE	$T_A = -40^{\circ}\text{C to } + 105^{\circ}\text{C}$		±27		LOD
Gain Error Temperature Coefficient (Note 4)	TCGE		-2.5	±0.10	+2.5	ppm/°C of FSR
Output Voltage Range		No load	0		V _{AVDD} - 0.1	V

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ELECTRICAL CHARACTERISTICS (continued)

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PARAMETER	SYMBOL	CONE	OITIONS	MIN	TYP	MAX	UNITS
		DOT	$M/\overline{Z} = DGND$		75		μV
		RST = pulse low	$M/\overline{Z} = V_{DDIO}$		2.048		V
		\overline{RST} = pulse low,	$M/\overline{Z} = DGND$		10		mV
Reset Voltage Output	V _{OUT-RESET}	$V_{AVSS} = 0V$ $M/\overline{Z} = V_{DDIO}$		2.048		V	
Theodi Vellage Salpat	*OUT-RESET	RST = DGND	$M/\overline{Z} = DGND$		-68		mV
			$M/\overline{Z} = V_{DDIO}$		2.036		V
		RST = DGND,	$M/\overline{Z} = DGND$		10		mV
		V _{AVSS} = 0V	$M/\overline{Z} = V_{DDIO}$		2.036		V
DC Output Impedance (Normal Mode)	R _{OUT}	Closed-loop connec to OUT)	tion (RFB connected		4		mΩ
Output Resistance (Power-Down Mode)		PD = V _{DDIO}			2		kΩ
Output Current	la=	Source/sink within 10 rails	00mV of the supply		±4		mA
Output Gurrent	lout	Source/sink within 800mV of the supply rails			±25		ША
Load Capacitance to GND	CL					200	рF
Load Resistance to GND	R_{L}	For specified perforr	nance	2			kΩ
		OUT shorted to AGND or AVDD			±60		
Short-Circuit Current	I _{SC}	REFO shorted to AG	±65			mA	
		BYPASS shorted to AGND or AVDD		±48			
Short-Circuit Duration	T _{SC}	Short to AGND or A\	/DD		Indefinite		S
DC Power-Supply Rejection	DC PSRR	V _{OUT} at full scale, V,	AVDD = 4.5V to 5.5V	-2.5	±0.20	+2.5	LSB/V
Do rower dupply riejection	DOTORIT	$V_{AVSS} = -1.5V \text{ to } -0.5$	5V	-2.5	±0.012	+2.5	LOD/ V
STATIC PERFORMANCE—VOLT	AGE REFER	ENCE INPUT SECTION	DN				
Reference High Input Range	V _{REF}			2.4		V _{AVDD} - 0.1	V
Reference Input Capacitance	C _{REF}				10		рF
Reference Input Resistance	R _{REF}				10		MΩ
Reference Input Current	I _B				±0.15		μA
STATIC PERFORMANCE—VOLT	AGE REFER	ENCE OUTPUT SEC	TION				
Reference High Output Range				2.4		V _{AVDD} - 0.1	V
Reference High Output Load Regulation					500		ppm/ mA
Reference Output Capacitor		$R_{\rm ESR} < 5\Omega$			0.1		nF

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PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
STATIC PERFORMANCE—VBYP	ASS OUT SE	CTION				
Output Voltage	V _{BYPASS}		2.3	2.4	2.5	V
Load Capacitance to GND	CL	Required for stability, $R_{ESR} = 0.1\Omega$ (typ)	1		8	μF
POWER-SUPPLY REQUIREMEN	TS					
Positive Analog Power-Supply Range	V _{AVDD}		4.5		5.5	V
Digital Interface Power-Supply Range	V _{DDIO}		1.8		V_{AVDD}	V
Negative Analog Power-Supply Range	V _{AVSS}		-1.5	-1.25	0	V
Positive Analog Power-Supply Current	I _{AVDD}	No load, external reference, output at zero scale		5.2	6.5	mA
Negative Analog Power-Supply Current	I _{AVSS}	No load, external reference, output at zero scale	-1.5	-1.0		mA
Interface Power-Supply Current	I _{VDDIO}	Digital inputs at V _{DDIO} or DGND		0.2	5.0	μΑ
Positive Analog Power-Supply Power-Down Current		PD = V _{DDIO} , power-down mode		20	50	μΑ
Negative Analog Power-Supply Power-Down Current		PD = V _{DDIO} , power-down mode	-5	-3		μΑ
DYNAMIC PERFORMANCE						
Voltage Output Slew Rate	SR	From 10% to 90% full scale, positive and negative transitions		4.9		V/µs
Voltage Output Settling Time	ts	From falling edge of LDAC to within 0.003% FS, R_L = 10k Ω , DIN = 04000h (6.25% FS) to 3C000h (93.75% FS)		3		μs
Busy Time	t _{BUSY}	(Note 5)		1.9		μs
DAC Glitch Impulse		Major code transition (1FFFFh to 20000h), $R_L = 10k\Omega$, $C_L = 50pF$		4		nVs
Digital Feed Through		CSB = V _{DDIO} , f _{SCLK} = 1kHz, all digital inputs from 0V to V _{DDIO}		1		nVs
Output Voltage-Noise Spectral Density		At f = 1kHz to 10kHz, without reference, code = 20000h		26		nV/√Hz
Output Voltage Noise		At f = 0.1Hz to 10Hz, without reference, code = 20000h		1.55		μV _{P-P}
Wake-Up Time		From power-down mode		75		μs
Power-Up Time		From power-off		2	<u> </u>	ms

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ELECTRICAL CHARACTERISTICS

 $(V_{AVDD} = V_{DDIO} = \textbf{2.7V to 3.3V}, V_{AVSS} = -1.25 \text{V}, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0 \text{V}, V_{REF} = 2.5 \text{V}, \text{TC}/\overline{SB} = \text{PD} = \overline{\text{LDAC}} = M/\overline{Z} = DGND, \overline{RST} = V_{DDIO}, C_{REFO} = 100 \text{pF}, C_L = 100 \text{pF}, R_L = 10 \text{k}\Omega, C_{BYPASS} = 1 \text{µF}, GAIN = 0x3FFFF}, OFFSET = 0x00000, T_A = -40 ^{\circ}\text{C} \text{ to } +105 ^{\circ}\text{C}, \text{ unless otherwise noted. Typical values are at } T_A = +25 ^{\circ}\text{C}.) \text{ (GAIN = 0x3FFFF and OFFSET = 0x00000.)} \text{(Note 2)}$

PARAMETER	SYMBOL	CON	DITIONS	MIN	TYP	MAX	UNITS
STATIC PERFORMANCE							
Resolution	N			18			Bits
Integral Marlingarity (Nata 2)	INII	DIN = 0x00000 to 0 mode), DIN = 0x200 complement mode)	000 to 0x1FFFF (two's	0.0	. 0. 75	.00	LCD
Integral Nonlinearity (Note 3)	INL	DIN = 0x01900 to 0 mode), DIN = 0x219 complement mode)	900 to 0x1FFFF (two's	-2.0	±0.75	+2.0	LSB
Differential Nonlinearity (Note 3)	DNL			-1.0	±0.3	+1.0	LSB
7 0 1 5	0.5	DIN = 0, $T_A = +25^\circ$	C	-50	±6	+50	1.00
Zero Code Error	OE	DIN = 0, $T_A = -40^{\circ}C$	C to +105°C		±25		LSB
Zero Code Error Drift (Note 4)		DIN = 0		-2.7	±1.4	+2.7	ppm/°C
Onlin France	0.5	$T_A = +25^{\circ}C$		-16	±1.5	+16	1.00
Gain Error	GE	$T_A = -40^{\circ}\text{C to} + 105^{\circ}$	°C		±35		LSB
Gain Error Temperature Coefficient (Note 4)	TCGE			-3.2		+3.2	ppm/°C of FSR
Output Voltage Range		No load		0		V _{AVDD} - 0.1	V
	-	$M/\overline{Z} = DGND$	$M/\overline{Z} = DGND$		75		μV
			RST = pulse low	$M/\overline{Z} = V_{DDIO}$		1.25	
		RST = pulse low,	$M/\overline{Z} = DGND$		10		mV
Reset Voltage Output	\/ o = = = = = =	$V_{AVSS} = 0V$	$M/\overline{Z} = V_{DDIO}$		1.25		V
Theset Voltage Output	V _{OUT-RESET}	DOT DONE	$M/\overline{Z} = DGND$		-40		mV
		RST = DGND	$M/\overline{Z} = V_{DDIO}$		1.25		V
		RST = DGND,	$M/\overline{Z} = DGND$		10		mV
		$V_{AVSS} = 0V$	$M/\overline{Z} = V_{DDIO}$		1.24		V
DC Output Impedance	R _{OUT}	Closed-loop connecto OUT	ction, RFB connected		4		mΩ
Output Current	la	Source/sink within 10	00mV of the supply rails		±4		m A
Output Guirent	lout	Source/sink within 80	00mV of the supply rails		±25		mA
Load Capacitance to GND	CL					200	pF
Load Resistance to GND	RL	For specified perfor	mance	2			kΩ
		OUT shorted to AGND or AVDD			±60		
Short-Circuit Current	I _{SC}	REFO shorted to AGND or AVDD			±65		mA
		BYPASS shorted to			±48		
Short-Circuit Duration	t _{SC}	Short to AGND or A		Indefinite		S	

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ELECTRICAL CHARACTERISTICS (continued)

 $(V_{AVDD} = V_{DDIO} = \textbf{2.7V to 3.3V}, V_{AVSS} = -1.25V, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0V, V_{REF} = 2.5V, TC/\overline{SB} = PD = \overline{LDAC} = M/\overline{Z} = DGND, \overline{RST} = V_{DDIO}, C_{REFO} = 100pF, C_L = 100pF, R_L = 10k\Omega, C_{BYPASS} = 1\mu F, GAIN = 0x3FFFF, OFFSET = 0x00000, T_A = -40°C to +105°C, unless otherwise noted. Typical values are at <math>T_A = +25°C$.) (GAIN = 0x3FFFF and OFFSET = 0x00000.)(Note 2)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
DO Davia Comarko Dala ati	DODODO	V _{OUT} at full scale, V _{AVDD} = 2.7V to 3.3V	-2.5	±0.4	+2.5	L CDA/
DC Power-Supply Rejection	DCPSRR	$V_{AVSS} = -1.5V \text{ to } -0.5V$	-2.5	±0.04	+2.5	LSB/V
STATIC PERFORMANCE—VOLT	AGE REFER	RENCE INPUT SECTION				
Reference High Input Range	V _{REF}		2.4		V _{AVDD} - 0.1	V
Reference Input Capacitance	C _{REF}			10		pF
Reference Input Resistance	R _{REF}			10		ΜΩ
Reference Input Current	IB			±0.15		μΑ
STATIC PERFORMANCE—VOLT	AGE REFER	RENCE OUTPUT SECTION				r
Reference High Output Range			2.4		V _{AVDD} - 0.1	V
Reference High Output Load Regulation				500		ppm/mA
Reference Output Capacitor		$R_{\rm ESR} < 5\Omega$		0.1		nF
STATIC PERFORMANCE—VBYP	ASS OUT SE	CTION				
Output Voltage	V _{BYPASS}		2.3	2.4	2.5	V
Load Capacitance to GND	CL	Required for stability, $R_{ESR} = 0.1\Omega$ (typ)	1		8	μF
POWER-SUPPLY REQUIREMEN	TS					
Positive Analog Power-Supply Range	V _{AVDD}		2.7		3.3	V
Interface Power-Supply Range	V _{DDIO}		1.8		5.5	V
Negative Analog Power-Supply Range	V _{AVSS}		-1.5	-1.25	0	٧
Positive Analog Power-Supply Current	I _{AVDD}	No load, external reference, output at zero scale		5.0	6.5	mA
Negative Analog Power-Supply Current	I _{AVSS}	No load, external reference, output at zero scale	-1.5	-0.8		mA
Interface Power-Supply Current	I _{VDDIO}	Digital inputs at V _{DDIO} or DGND		0.2	5.0	μΑ
Positive Analog Power-Supply Power-Down Current		PD = V _{DDIO} , power-down mode		20	50	μΑ
Negative Analog Power-Supply Power-Down Current		PD = V _{DDIO} , power-down mode	-5	-2		μΑ
DYNAMIC PERFORMANCE	1					
Voltage Output Slew Rate	SR	From 10% to 90% full scale, positive and negative transitions		4.9		V/µs
Voltage Output Settling Time	ts	From falling edge of LDAC to within 0.003% FS, R_L = 10k Ω , DIN = 04000h (6.25% FS) to 3C000h (93.75% FS)		3		μs

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ELECTRICAL CHARACTERISTICS (continued)

 $(V_{AVDD} = V_{DDIO} = \textbf{2.7V to 3.3V}, V_{AVSS} = -1.25V, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0V, V_{REF} = 2.5V, TC/\overline{SB} = PD = \overline{LDAC} = M/\overline{Z} = DGND, \overline{RST} = V_{DDIO}, C_{REFO} = 100pF, C_L = 100pF, R_L = 10k\Omega, C_{BYPASS} = 1\mu F, GAIN = 0x3FFFF, OFFSET = 0x00000, T_A = -40°C to +105°C, unless otherwise noted. Typical values are at <math>T_A = +25°C$.) (GAIN = 0x3FFFF and OFFSET = 0x00000.)(Note 2)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Busy Time	t _{BUSY}	(Note 5)		1.9		μs
DAC Glitch Impulse		Major code transition (1FFFFh to 20000h), R _L = $10k\Omega$, C _L = $50pF$		2.5		nVs
Digital Feedthrough		CSB = V _{DDIO} , f _{SCLK} = 1kHz, all digital inputs from 0V to V _{DDIO}		1		nVs
Output Voltage-Noise Spectral Density		At f = 1kHz to 10kHz, without reference, code = 20000h		26		nV/√Hz
Output Voltage Noise		At f = 0.1Hz to 10Hz, without reference, code = 20000h		1.55		μV _{P-P}
Wake-Up Time		From power-down mode		75		μs
Power-Up Time		From power-off		2		ms

DIGITAL INTERFACE ELECTRICAL CHARACTERISTICS

 $(V_{AVDD} = 5V, V_{DDIO} = \textbf{2.7V} \text{ to 5.5V}, V_{AVSS} = -1.25V, V_{REF} = 4.096V, R_L = 10k\Omega, TC/\overline{SB} = M/\overline{Z} = DGND, C_{REFO} = 100pF, C_{BYPASS} = 1\mu F, T_A = -40^{\circ}C$ to +105°C, unless otherwise noted. Typical values are at $T_A = +25^{\circ}C$.)(GAIN = 0x3FFFF and OFFSET = 0x000000.) (Note 2)

(Note 2)						
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
DIGITAL INPUTS (SCLK, DIN, CS	S, LDAC, M/Z	, RST)				
Input High Voltage	V _{IH}		0.7 x V _{DDIO}			V
Input Low Voltage	V _{IL}				0.3 x V _{DDIO}	V
Input Hysteresis (Note 4)	V _{IHYST}		200	300		mV
Input Leakage Current	I _{IN}			±0.1	±1	μΑ
Input Capacitance	C _{IN}			10		рF
DIGITAL OUTPUT CHARACTERI	STICS (DOU	T, READY, BUSY)				
Output Low Voltage	V _{OL}	I _{SOURCE} = 5.0mA			0.25	V
Output High Voltage	V _{OH}	I _{SINK} = 5.0mA, except for BUSY	V _{DDIO} - 0.25			V
Output Three-State Leakage	loz	DOUT only		±0.1	±1	μΑ
Output Three-State Capacitance	C _{OZ}	DOUT only		15		рF
Output Short-Circuit Current	loss	V _{DDIO} = 5.25V		±150		mA

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DIGITAL INTERFACE ELECTRICAL CHARACTERISTICS (continued)

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PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
TIMING CHARACTERISTICS	•						
		Stand-alone, v	vrite mode			50	
Serial Clock Frequency	f _{SCLK}		Stand-alone, read mode and daisy-chained read and write modes (Note 5)			12.5	MHz
		Stand-alone, v	vrite mode	20			
SCLK Period	t _{CP}		ead mode and daisy- and write modes	80			ns
SCLK Pulse Width High	t _{CH}	40% duty cycl	e	8			ns
SCLK Pulse Width Low	t _{CL}	40% duty cycl	e	8			ns
			Stand-alone, write mode	8			
CS Fall to SCLK Fall Setup Time	t _{CSSO}	First SCLK falling edge	Stand-alone, read mode and daisy-chained read and write modes	38			ns
CS Fall to SCLK Fall Hold Time	t _{CSH0}	Inactive falling edge	edge preceding first falling	0			ns
SCLK Fall to CS Rise Hold Time	t _{CSH1}	24th falling ed	ge	2			ns
DIN to SCLK Fall Setup Time	t _{DS}			5			ns
DIN to SCLK Fall Hold Time	t _{DH}			4.5			ns
SCLK Rise to DOUT Settle Time	t _{DOT}	$C_L = 20pF (No$	ote 6)			32	ns
SCLK Rise to DOUT Hold Time	t _{DOH}	$C_L = 0pF (Not)$	e 6)	2			ns
SCLK Fall to DOUT Disable Time	t _{DOZ}	24th active ed	ge deassertion	2		30	ns
CS Fall to DOUT Enable	t _{DOE}	Asynchronous	assertion	2		30	ns
CS Rise to DOUT Disable	t _{CSDOZ}	Stand-alone, a	aborted sequence			35	ns
	CSDOZ	Daisy-chained, aborted sequence				70	110
SCLK Fall to READY Fall	tCRF		lge assertion, C _L = 20pF			30	ns
SCLK Fall to READY Hold	t _{CRH}		lge assertion, C _L = 0pF	2			ns
SCLK Fall to BUSY Fall	t _{CBF}	BUSY assertion	on		5		ns
CS Rise to READY Rise	t _{CSR}	$C_L = 20pF$				35	ns
CS Rise to SCLK Fall	t _{CSA}	24th falling edge, aborted sequence		20			ns
CS Pulse Width High	t _{CSPW}	Stand alone		20		_	ns
SCLK Fall to CS Fall	t _{CSF}	24th falling edge		100			ns
LDAC Pulse Width	t _{LDPW}			20			ns
LDAC Fall to SCLK Fall Hold	t _{LDH}	Last active fal	20			ns	
RST Pulse Width	t _{RSTPW}		20			ns	

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

DIGITAL INTERFACE ELECTRICAL CHARACTERISTICS

 $(V_{AVDD} = 5V, V_{DDIO} =$ **1.8V to 2.7V**, $V_{AVSS} = -1.25V$, $V_{REF} = 4.096V$, $R_L = 10k\Omega$, $TC/\overline{SB} = M/\overline{Z} = DGND$, $C_{REFO} = 100pF$, $C_{BYPASS} = 1\mu F$, $T_A = -40^{\circ}C$ to $+105^{\circ}C$, unless otherwise noted. Typical values are at $T_A = +25^{\circ}C$.)(GAIN = 0x3FFFF and OFFSET = 0x000000.) (Note 2)

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
DIGITAL INPUTS (SCLK, DIN, CS	S, LDAC, M/Z	, RST)					
Input High Voltage	V _{IH}			0.8 x V _{DDIO}			V
Input Low Voltage	V _{IL}					0.2 x V _{DDIO}	V
Input Hysteresis (Note 4)	V _{IHYST}			200	300		mV
Input Leakage Current	I _{IN}	Input = 0V at	V _{DDIO}		±0.1	±1	μΑ
Input Capacitance	C _{IN}				10		pF
DIGITAL OUTPUTS CHARACTE	RISTICS (DO	UT, READY, BI	JSY)				
Output Low Voltage	V _{OL}	I _{SOURCE} = 1.0	OmA			0.2	V
Output High Voltage	V _{OH}	I _{SINK} = 1.0mA	A, except for BUSY	V _{DDIO} - 0.2			V
Output Three-State Leakage	I _{OZ}	DOUT only			±0.1	±1	μΑ
Output Three-State Capacitance	C _{OZ}	DOUT only			15		рF
Output Short-Circuit Current	I _{OSS}	$V_{DDIO} = 2.7V$		±150		mA	
TIMING CHARACTERISTICS		_					
		Stand-alone v	vrite mode			50	
Serial Clock Frequency	fsclk		Stand-alone read mode and daisy- chained read and write modes (Note 6)			8	MHz
		Stand-alone v	vrite mode	20			
SCLK Period	t _{CP}	1	ead mode and daisy- and write modes	125			ns
SCLK Pulse-Width High	t _{CH}	40% duty cyc	le	9			ns
SCLK Pulse-Width Low	t _{CL}	40% duty cyc	le	9			ns
			Stand-alone write mode	12			
CS Fall to SCLK Fall Setup Time	t _{CSSO}	First SCLK falling edge	Stand-alone read mode and daisy-chained read and write modes	72			ns
CS Fall to SCLK Fall Hold Time	t _{CSH0}	Inactive falling edge preceding first falling edge		0			ns
SCLK Fall to CS Rise Hold Time	t _{CSH1}	24th falling edge		4			ns
DIN to SCLK Fall Setup Time	t _{DS}			8			ns
DIN to SCLK Fall Hold Time	t _{DH}			8			ns
SCLK Rise to DOUT Settle Time	t _{DOT}	C _L = 20pF (N	ote 7)			40	ns
SCLK Rise to DOUT Hold Time	t _{DOH}	C _L = 0pF (No	te 7)	2			ns

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

DIGITAL INTERFACE ELECTRICAL CHARACTERISTICS (continued)

 $(V_{AVDD} = 5V, V_{DDIO} =$ **1.8V to 2.7V** $, V_{AVSS} = -1.25V, V_{REF} = 4.096V, R_L = 10k\Omega, TC/\overline{SB} = M/\overline{Z} = DGND, C_{REFO} = 100pF, C_{BYPASS} = 1\mu F, T_A = -40^{\circ}C$ to +105°C, unless otherwise noted. Typical values are at $T_A = +25^{\circ}C.$)(GAIN = 0x3FFFF and OFFSET = 0x00000.) (Note 2)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
SCLK Fall to DOUT Disable Time	t _{DOZ}	24th active edge deassertion	2		40	ns
CS Fall to DOUT Enable	t _{DOE}	Asynchronous assertion	2		50	ns
CS Rise to DOUT Disable	+	Stand-alone, aborted sequence			70	20
CS Rise to DOUT Disable	t _{CSDOZ}	Daisy-chained, aborted sequence			130	ns
SCLK Fall to READY Fall	tCRF	24th falling edge assertion, C _L = 20pF			60	ns
SCLK Fall to READY Hold	tcrh	24th falling edge assertion, C _L = 0pF	2			ns
SCLK Fall to BUSY Fall	t _{CBF}	BUSY assertion		5		ns
CS Rise to READY Rise	t _{CSR}	$C_L = 20pF$			60	ns
CS Rise to SCLK Fall	t _{CSA}	24th falling edge, aborted sequence	20			ns
CS Pulse Width High	tCSPW	Stand alone	20			ns
SCLK Fall to CS Fall	t _{CSF}	24th falling edge	100			ns
LDAC Pulse Width	t _{LDPW}		20			ns
LDAC Fall to SCLK Fall Hold	t _{LDH}	Last active falling edge	20			ns
RST Pulse Width	t _{RSTPW}		20			ns

Note 2: All devices are 100% tested at $T_A = +25^{\circ}C$ and $T_A = +105^{\circ}C$. Limits at $T_A = -40^{\circ}C$ are guaranteed by design.

Note 3: Linearity is tested from V_{REF} to AGND.

Note 4: Guaranteed by design.

Note 5: The total analog throughput time from DIN to V_{OUT} is the sum of t_S and t_{BUSY} (4.9 μs , typ).

Note 6: Daisy-chain speed is relaxed to accommodate (t_{CRF} + t_{CSS0}).

Note 7: DOUT speed limits overall SPI speed..

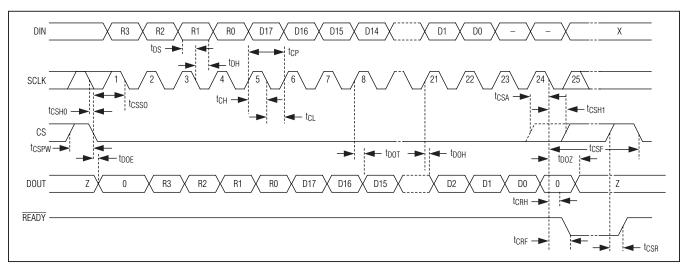
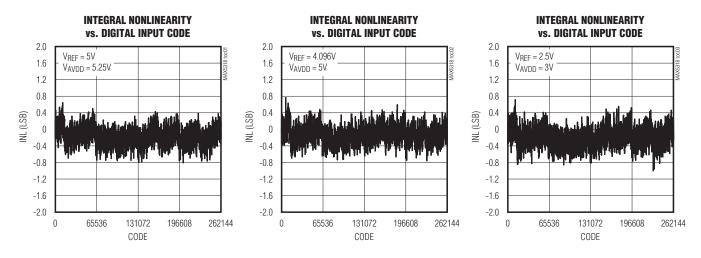


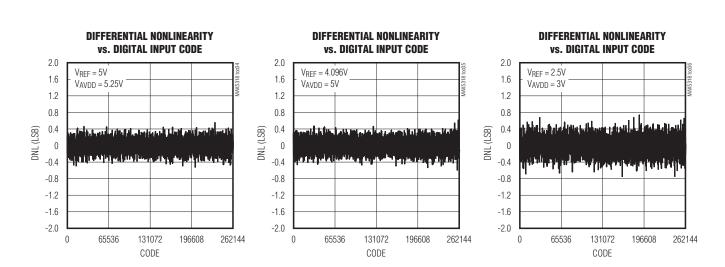
Figure 1. Serial Interface Timing Diagram, Stand-Alone Operation

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Typical Operating Characteristics

 $\frac{(V_{AVDD} = V_{DDIO} = 5V, \, V_{AVSS} = -1.25V, \, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0V; \, V_{REF} = 4.096V, \, TC/\overline{SB} = PD = M/\overline{Z} = DGND, \, RST = V_{DDIO}, \, C_{REFO} = 100pF, \, C_L = 100pF, \, R_L = 10k\Omega, \, C_{BYPASS} = 1\mu F, \, T_A = +25^{\circ}C, \, unless \, otherwise \, noted.)$

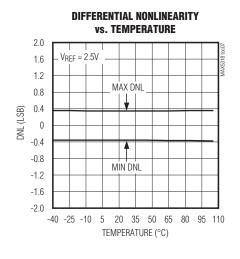


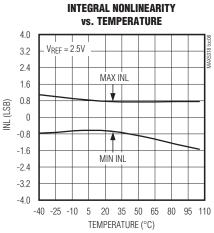


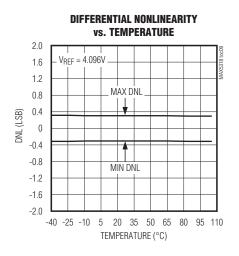
18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

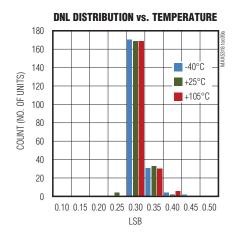
Typical Operating Characteristics (continued)

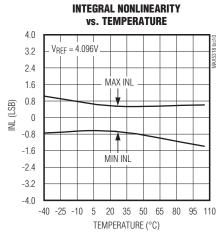
 $\frac{(V_{AVDD} = V_{DDIO} = 5V, \, V_{AVSS} = -1.25V, \, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0V; \, V_{REF} = 4.096V, \, TC/\overline{SB} = PD = M/\overline{Z} = DGND, \, RST = V_{DDIO}, \, C_{REFO} = 100pF, \, C_L = 100pF, \, R_L = 10k\Omega, \, C_{BYPASS} = 1\mu F, \, T_A = +25^{\circ}C, \, unless \, otherwise \, noted.)$

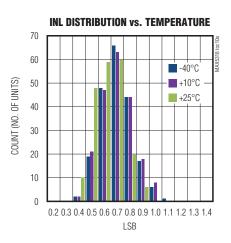








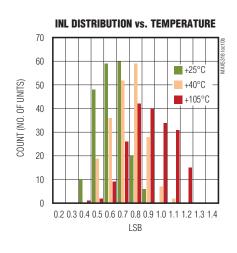


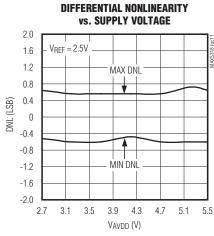


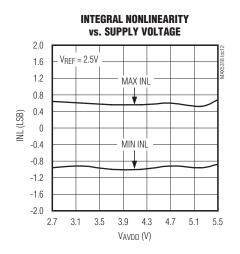
18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

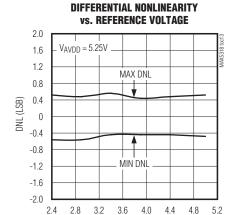
Typical Operating Characteristics (continued)

 $\frac{(V_{AVDD} = V_{DDIO} = 5V, V_{AVSS} = -1.25V, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0V; V_{REF} = 4.096V, TC/\overline{SB} = PD = M/\overline{Z} = DGND, \overline{RST} = V_{DDIO}, C_{REFO} = 100pF, C_L = 100pF, R_L = 10k\Omega, C_{BYPASS} = 1\mu F, T_A = +25^{\circ}C, unless otherwise noted.)$

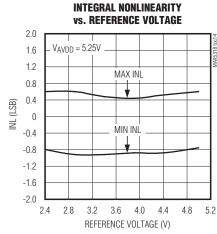


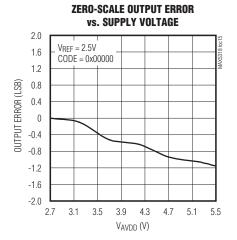






REFERENCE VOLTAGE (V)

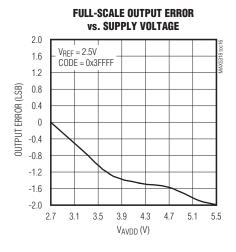


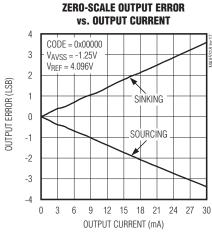


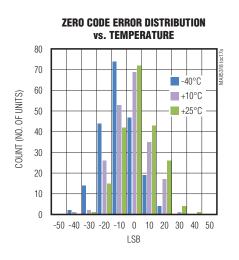
18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

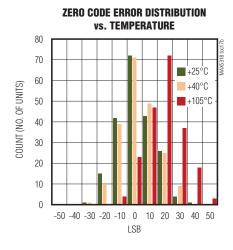
Typical Operating Characteristics (continued)

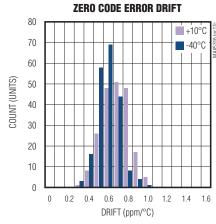
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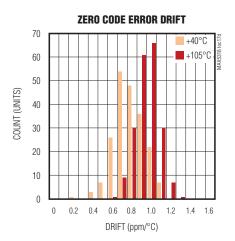








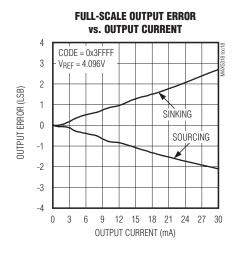


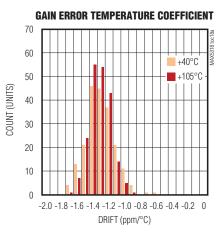


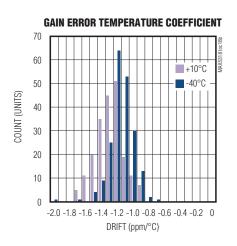
18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

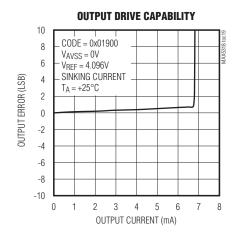
Typical Operating Characteristics (continued)

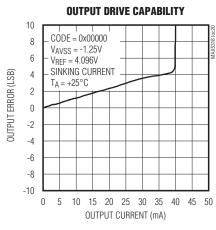
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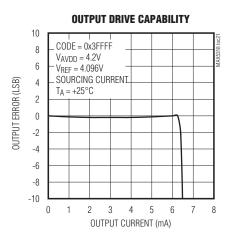








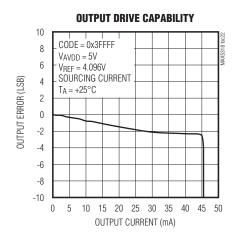


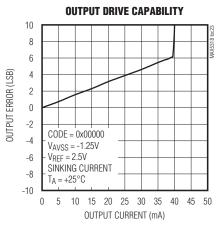


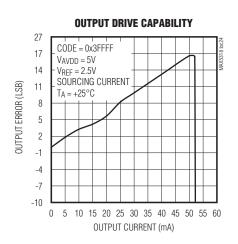
18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

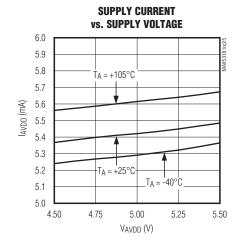
Typical Operating Characteristics (continued)

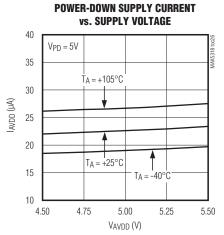
 $\frac{(V_{AVDD} = V_{DDIO} = 5V, \, V_{AVSS} = -1.25V, \, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0V; \, V_{REF} = 4.096V, \, TC/\overline{SB} = PD = M/\overline{Z} = DGND, \, \overline{RST} = V_{DDIO}, \, C_{REFO} = 100pF, \, C_L = 100pF, \, R_L = 10k\Omega, \, C_{BYPASS} = 1\mu F, \, T_A = +25^{\circ}C, \, unless \, otherwise \, noted.)$







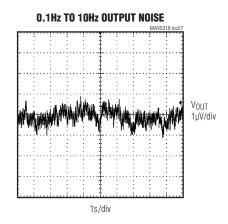


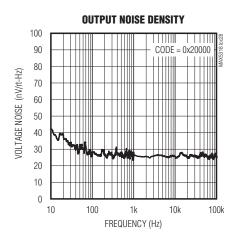


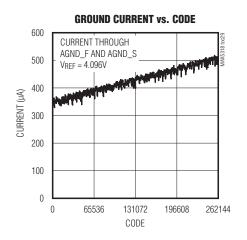
18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

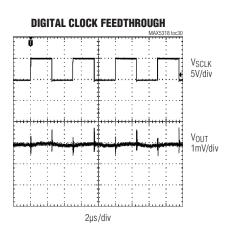
Typical Operating Characteristics (continued)

 $\frac{(V_{AVDD} = V_{DDIO} = 5V, \, V_{AVSS} = -1.25V, \, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0V; \, V_{REF} = 4.096V, \, TC/\overline{SB} = PD = M/\overline{Z} = DGND, \, RST = V_{DDIO}, \, C_{REFO} = 100pF, \, C_L = 100pF, \, R_L = 10k\Omega, \, C_{BYPASS} = 1\mu F, \, T_A = +25^{\circ}C, \, unless \, otherwise \, noted.)$





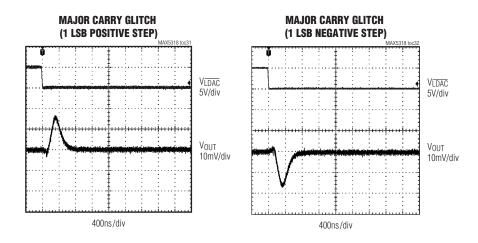


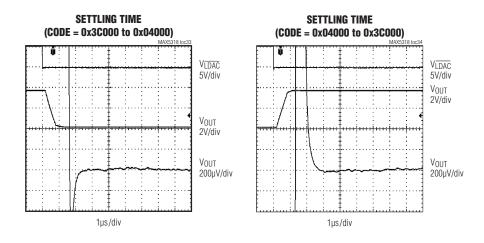


18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Typical Operating Characteristics (continued)

 $\frac{(V_{AVDD} = V_{DDIO} = 5V, \, V_{AVSS} = -1.25V, \, V_{AGND} = V_{DGND} = V_{AGND_F} = V_{AGND_S} = 0V; \, V_{REF} = 4.096V, \, TC/\overline{SB} = PD = M/\overline{Z} = DGND, \, RST = V_{DDIO}, \, C_{REFO} = 100pF, \, C_L = 100pF, \, R_L = 10k\Omega, \, C_{BYPASS} = 1\mu F, \, T_A = +25^{\circ}C, \, unless \, otherwise \, noted.)$

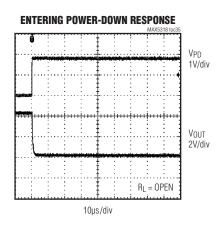


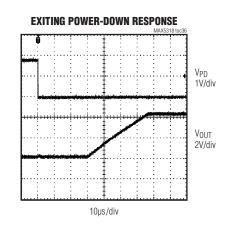


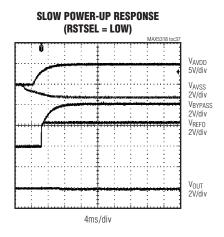
18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

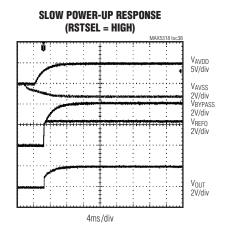
Typical Operating Characteristics (continued)

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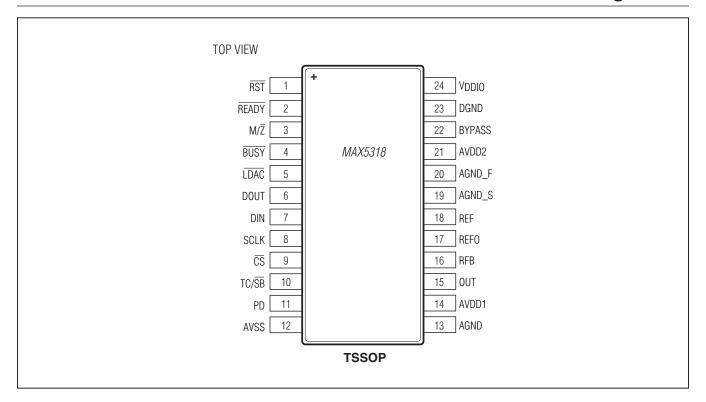






18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Pin Configuration



Pin Description

PIN	NAME	FUNCTION
1	RST	Active-Low Reset Input. Drive \overline{RST} low to DGND to put the device into a reset state. A reset state sets all SPI input registers to their default power-on reset states as defined by the state of inputs M/ \overline{Z} and TC/ \overline{SB} . Set \overline{RST} high to VDDIO, the DAC output remains at the state defined by M/ \overline{Z} until \overline{LDAC} is taken low.
2	READY	SPI Active-Low Ready Output. READY asserts low when the device successfully completes processing an SPI data frame. READY asserts high at the next rising edge of \overline{CS} . In daisy-chain applications, the READY output typically drives the \overline{CS} input of the next device in the chain or a GPIO of a microcontroller.
3	M/Z	Reset Select Input. M/\overline{Z} selects the default state of the analog output (OUT) after power-on or a hardware or software reset. Connect M/\overline{Z} to V_{DDIO} to set the default output voltage to midscale or to DGND to set the default output voltage to zero scale.
4	BUSY	Digital Input/Open-Drain Output. Connect a $2k\Omega$ pullup resistor from \overline{BUSY} to V_{DDIO} . \overline{BUSY} goes low during the internal calculations of the DAC register data. During this time, the user can continue writing new data to the DIN, OFFSET, and GAIN registers, but no further updates to the DAC register and DAC output can take place. If \overline{LDAC} is asserted low while \overline{BUSY} is low, this event is stored. \overline{BUSY} is bidirectional, and can be asserted low externally to delay \overline{LDAC} action. \overline{BUSY} also goes low during power-on reset, when \overline{RST} is low, or when software reset is activated.

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Pin Description (continued)

		=:wo=rov								
PIN	NAME	FUNCTION								
5	LDAC	Active-Low Load DAC Logic Input. If $\overline{\text{LDAC}}$ is taken low while $\overline{\text{BUSY}}$ is inactive (high), the contents of the input registers are transferred to the DAC register and the DAC output is updated. If $\overline{\text{LDAC}}$ is taken low while $\overline{\text{BUSY}}$ is asserted low, the $\overline{\text{LDAC}}$ event is stored and the DAC register update is delayed until $\overline{\text{BUSY}}$ deasserts. Any event on $\overline{\text{LDAC}}$ during power-on reset or when $\overline{\text{RST}}$ is low is ignored.								
6	DOUT	SPI Bus Serial Data Output. See the Serial Interface section for details.								
7	DIN	SPI Bus Serial Data Input. See the Serial Interface section for details.								
8	SCLK	SPI Bus Serial Clock Input. See the Serial Interface section for details.								
9	CS	SPI Bus Active-Low Chip-Select Input. See the Serial Interface section for details.								
10	TC/SB	DIN Format Select Input. Connect TC/SB to DGND to set the data input format to straight binary or to VDDIO to set it to two's complement.								
11	PD	Active-High Power-Down Input. Connect PD to DGND for normal operation. Connect PD to V_{DDIO} to place the device in power-down. In power-down, OUT (analog voltage output) is connected to AGND through a $2k\Omega$ resistor, but the contents of the input registers and the DAC latch do not change. The SPI interface remains active in power-down.								
12	AVSS	Negative Analog Power-Supply Input. Connect to AGND or a negative supply voltage. When connected to the negative supply voltage, bypass AVSS with a 0.1µF capacitor to AGND.								
13	AGND	Analog Ground. Connect to the analog ground plane.								
14	AVDD1	Positive Analog Power-Supply Input. Bypass each AVDD_ locally with a 0.1µF and 10µF capacitor to AGND (analog ground plane). Connect AVDD1 and AVDD2 together.								
15	OUT	Buffered Analog Voltage Output. Connect OUT to RFB externally to close the output buffer feedback loop. The buffered output is capable of directly driving a $10k\Omega$ load. The state of M/Z sets the power-on reset state of OUT (zero or midscale). In power-down, OUT is connected to AGND through a $2k\Omega$ pulldown resistor.								
16	RFB	Feedback Resistor Input. RFB is connected through the internal feedback resistor to the inverting input of the analog output buffer. Externally connect RFB to OUT to close the output buffer feedback loop.								
17	REFO	Voltage Reference Buffered Output. Bypass with a 100pF capacitor to AGND.								
18	REF	High-Impedance 10MΩ Voltage Reference Input								
19	AGND_S	DAC Analog Ground Sense								
20	AGND_F	DAC Analog Ground Force. Connect to the analog ground plane.								
21	AVDD2	Positive Analog Power-Supply Input. AVDD2 supplies power to the internal digital linear regulator. Bypass AVDD2 locally to AGND with 0.1µF and 10µF capacitors. Connect AVDD2 and AVDD1 together.								
22	BYPASS	Internal Bypass Connection. Connect BYPASS to DGND with 0.01µF and 1µF capacitors.								
23	DGND	Digital Ground								
24	V _{DDIO}	Digital Interface Power-Supply Input. Connect to a 1.8V to 5.5V logic-level supply. Bypass V _{DDIO} with a 0.1µF capacitor to DGND. The supply voltage at V _{DDIO} sets the logic-level for the digital interface.								

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Detailed Description

The MAX5318 is a high-accuracy, 18-bit, serial SPI input, buffered voltage output digital-to-analog converter (DAC) in a 4.4mm x 7.8mm, 24-lead TSSOP package. The device features ±2 LSB INL (max) accuracy and a ±1 LSB DNL (max) accuracy over the full temperature range of -40°C to +105°C.

The DAC voltage output is buffered resulting in a fast settling time of $3\mu s$ and a low offset and gain drift of $\pm 0.5 ppm/^{\circ}C$ of FSR (typ). The force-sense output (OUT) maintains accuracy while driving loads with long lead lengths. Additionally, a separate AVSS supply allows the output amplifier to go to 0V (GND) while maintaining full linearity performance.

The MAX5318 includes user-programmable digital gain and offset correction capability to enable easy system calibration.

At power-up, the device resets its outputs to zero or mid-scale, providing additional safety for applications, which drive valves or other transducers that need to be off on power-up. This is selected by the state of the M/\overline{Z} input on power-up.

The wide 2.7V to 5.5V supply voltage range and integrated low-drift, low-noise reference buffer amplifier makes for ease of use. Since the reference buffer input has a high input resistance, an external buffer is not required. The device accepts an external reference between 2.4V and V_{AVDD} - 0.1V for maximum flexibility and rail-to-rail operation.

The MAX5318 features a 50MHz, 3-wire SPI, QSPI, MICROWIRE, and DSP-compatible serial interface. The separate digital interface supply voltage input (V_{DDIO}) is compatible with a wide range of digital logic levels from 1.8V to 5.5V, eliminating the need for separate voltage translators.

DAC Reference Buffer

The external reference input has a high input (REF) impedance of $10M\Omega II10pF$ and accepts an input voltage from +2.4V to V_{AVDD} - 0.1V. Connect an external reference supply between REF and AGND. Bypass the reference buffer output REFO to AGND with a 100pF capacitor. Connect the anode of an external Schottky diode to REF and the cathode to AVDD1 to prevent internal ESD diode conduction in the event that the reference voltage comes

up before AVDD at power up. Follow the recommendations described in the *Power-Supply Sequencing* section.

Visit <u>www.maximintegrated.com/products/references</u> for a list of available external voltage-reference devices.

Output Amplifier (OUT)

The MAX5318 includes an internal buffer for the DAC output. The internal buffer provides improved load regulation for the DAC output. The output buffer slews at 5V/µs and drives up to $2k\Omega$ in parallel with 200pF. The buffer has a rail-to-rail output capable of swinging to within 100mV of AVDD_ and AVSS.

The positive analog supply voltage (AVDD_) determines the maximum output voltage of the device as AVDD_ powers the output buffer.

The output is diode clamped to ground, preventing negative voltage excursions beyond approximately -0.6V.

Negative Supply Voltage (AVSS)

The negative supply voltage (AVSS) determines the minimum output voltage. If AVSS is connected to ground, the output voltage can be set to as low as 100mV without degrading linearity. For operation down to 0V, connect AVSS to a negative supply voltage between -0.1V and -1.5V. The MAX1735 is recommended for generating -1.25V from a -5V supply.

Force/Sense

The MAX5318 uses force/sense techniques to ensure that the load is regulated to the desired output voltage despite line drops due to long lead lengths. Since AGND_F and AGND_S have code dependent ground currents, a ground impedance less than 13m Ω ensures that the INL will not degrade by more than 0.1 LSB. Form a star ground connection (Figure 2a) near the device with AGND_F, AGND_S, and AGND tied together. Always refer remote DAC loads to this system ground for best performance. Figure 2b shows how to configure the device and an external op amp for proper force/sense operation. The amplifier provides as much drive as needed to force the sensed voltage (measured between RFB and AGND_S) to equal the desired voltage.

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

18-Bit Ideal Transfer Function

The MAX5318 features 18-bit gain and 18-bit offset adjustment as shown in Figure 3.

The incoming DIN code is multiplied and offset compensated by the generic equation shown in Equation 1. The resulting value is then applied to the DAC.

Equation 1) Generic gain and offset adjustment

$$DAC = DIN \times GAIN + OFFSET$$

The GAIN code is always an 18-bit straight binary word. The OFFSET code is always two's complement. It is therefore simply added to the output of the multiplier.

To guarantee that a gain of exactly 1 is possible, the actual gain coefficient applied to DIN is as defined in Equation 2.

Equation 2) Calculation of gain

$$G = \frac{(GAIN) + 1}{2^{18}}$$

When DIN is straight binary, the ideal transfer function is given by:

Equation 3) Straight binary ideal transfer function

$$V_{OUT} = G \times V_{DIN} + V_{OFFSET}$$

When DIN is two's complement, the ideal transfer function is given by:

Equation 4) Two's complement ideal transfer function

$$V_{OUT} = \frac{V_{REF}}{2} + G \times V_{DIN} + V_{OFFSET}$$

 V_{DIN} and V_{OFFSET} are the voltages to which the DIN and OFFSET codes are converted and V_{OUT} is the voltage at the DAC output buffer. See the $\underline{\textit{Conversion Formulas for DIN, GAIN, and OFFSET}}$ section for equations needed to convert the DIN and OFFSET codes into V_{DIN} and V_{OFFSET} .

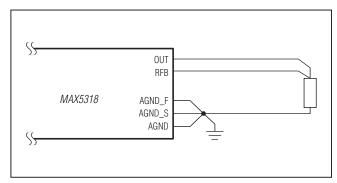


Figure 2a. Star Ground Connection

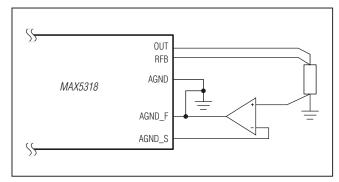


Figure 2b. Force/Sense Connection

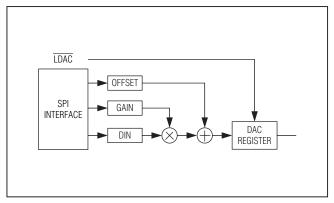


Figure 3. Gain and Offset Adjustment

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The data DIN can be either straight binary or two's complement. In straight binary, zero code results in a zero-scale output. In two's complement, zero code results in a midscale output.

To better understand how GAIN and OFFSET affect the output voltage, see Figure 4 and Figure 5. Consider the generation of a ramp. For now assume OFFSET is set to 0x00000. In straight binary mode, with GAIN set to 0x3FFFF (G = 1), DIN starts from 0x00000 and increases to 0x3FFFF. The output voltage will start at 0V and increase to (VREF - 1 LSB). If GAIN is reduced, the ramp will still start at 0V but the maximum level reached is reduced.

With DIN set to two's complement mode, to generate the same ramp, DIN would start at 0x20000 and increase until it wraps around to 0x00000. At this point the DAC output would be midscale. DIN then increases to 0x1FFFF where the output would be full-scale -1 LSB. As

GAIN is reduced, the start of the ramp becomes larger and the end of the ramp becomes smaller. The ramp is therefore centered at midscale.

In both cases, a nonzero value for OFFSET results in the output moving up or down.

Should the output of the gain and offset adjust block overflow full-scale or underflow zero-scale, the data is clipped so the DAC output will be clipped rather than overflow or underflow.

The effect of gain and offset adjustment is shown in Figure 4 for straight binary mode and Figure 5 for two's complement mode.

If any of the DIN, GAIN, or OFFSET registers is changed, the device takes 1.9 μ s (t_{BUSY}) to compute the new values to present to the DAC. While the device is computing the new DAC value, the $\overline{\text{BUSY}}$ output is set low. See the section on the $\overline{\text{BUSY}}$ output and $\overline{\text{LDAC}}$ input for details.

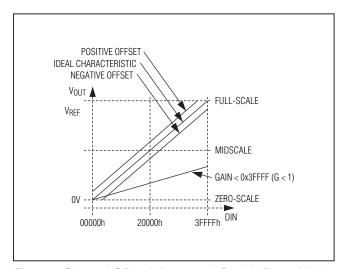


Figure 4. Gain and Offset Adjustment in Straight Binary Mode

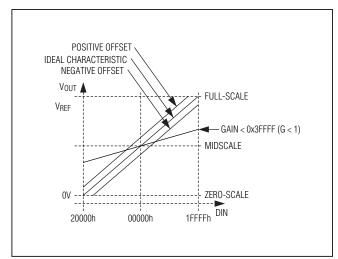


Figure 5. Gain and Offset Adjustment in Two's Complement Mode

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Conversion Formulas for DIN, GAIN, and OFFSET

Tables 1a and 1b show how to convert the DIN code to $V_{\mbox{DIN}}$ in straight binary and two's complement modes.

Table 2 shows how to convert the GAIN code to the gain factor G, which is multiplied with V_{DIN} . Table 3 shows how to convert the OFFSET code to V_{OFFSET} , which is summed with the product $G \bullet V_{DIN}$.

Input, Gain, and Offset Ranges

The ranges of DIN, GAIN, and OFFSET are summarized in <u>Table 4</u> to <u>Table 6</u>. Also shown are the range values for the 18-bit MAX5318 with a 4.096V reference. Note that V_{REF} is the reference voltage applied to REF and 1 LSB is equal to $V_{REF}/2^{18}$.

Table 1a. Converting DIN to V_{DIN} (Straight Binary Mode)

DIN	EQUATION FOR V _{DIN}	RANGE
0x000000 to 0x3FFFF	$V_{DIN} = V_{REF} \times \frac{DIN}{2^{18}}$	0V to (V _{REF} - 1 LSB)

Table 1b. Converting DIN to V_{DIN} (Two's Complement Mode)

DIN	EQUATION FOR V _{DIN} AND V _{OFFSET}	RANGE
0x20000 to 0x3FFFF	$V_{DIN} = V_{REF} \times \left(\frac{DIN - 0x20000}{2^{18}}\right) - \frac{V_{REF}}{2}$	V _{REF} /2 to -1 LSB
0x000000 to 0x1FFFF	$V_{DIN} = V_{REF} \times \frac{CODE}{2^{18}}$	0V to (V _{REF} /2 - 1 LSB)

Table 2. Converting GAIN to G

GAIN	EQUATION	RANGE
0x00000 to 0x3FFFF	$G = \frac{GAIN + 1}{2^{18}}$	1/2 ¹⁸ to 1

Table 3. Converting OFFSET to VOFFSET

OFFSET	EQUATION	RANGE
0x20000 to 0x3FFFF	$V_{OFFSET} = V_{REF} \times \left(\frac{OFFSET - 0x20000}{2^{18}}\right) - \frac{V_{REF}}{2}$	-VREF/2 to -1 LSB
0x000000 to 0x1FFFF	$V_{OFFSET} = V_{REF} \times \frac{OFFSET}{2^{18}}$	0V to (VREF/2 - 1 LSB)

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Table 4a. DIN Range (Straight Binary Mode)

RANGE	DIN	V _{DIN} (V)	VALUE (V)
Minimum	0x00000	0	0
Maximum	0x3FFFF	(V _{REF} - 1 LSB)	4.095984375

Table 4b. DIN Range (Two's Complement Mode)

RANGE	DIN	V _{DIN} (V)	VALUE (V)
Minimum	0x20000	0	0
Maximum	0x1FFFF	(V _{REF} - 1 LSB)	4.095984375

Table 5. GAIN Range

RANGE	GAIN	G	VALUE (V)
Minimum	0x00000	1/2 ¹⁸	0.000038147
Maximum	0x3FFFF	1	1

Table 6. OFFSET Range

RANGE	OFFSET	V _{OFFSET} (V)	VALUE (V)
Minimum	0x20000	-V _{REF} /2	-2.048
Maximum	0x1FFFF	(V _{REF} /2 - 1 LSB)	2.047992188

Table 7. Straight Binary DIN Examples

DIN	V _{DIN} (V)	GAIN	G	OFFSET	V _{OFFSET} (V)	CALCULATION	COMMENT
0x20000	2.048	0x2FFFF	0.75	0x10000	1.024	V _{OUT} = 0.75 x 2.048 + 1.024 = 2.56V	 For V_{OUT}, use Equation 3 For V_{DIN}, use Table 1a For G, use Table 2 For V_{OFFSET}, use Table 3 second formula
0x30000	3.072	0x0FFFF	0.25	0x30000	-1.024	V _{OUT} = 0.25 x 3.072 - 1.024 = 0.512V	 For V_{OUT}, use Equation 3 For V_{DIN}, use Table 1a For G, use Table 2 For V_{OFFSET}, use Table 3 first formula

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Table 8. Two's Complement DIN Examples

DIN	V _{DIN} (V)	GAIN	G	OFFSET	V _{OFFSET} (V)	CALCULATION	COMMENT
0x30000	-1.024	0x2FFFF	0.75	0x08000	0.512	V _{OUT} = 4.096/2 + 0.75 x (-1.024) + 0.512 = 1.792V	 For V_{OUT}, use Equation 4 For V_{DIN}, use Table 1b first formula For G, use Table 2 For V_{OFFSET}, use Table 3 second formula
0x10000	1.024	0x0FFFF	0.25	0x38000	-0.512	V _{OUT} = 4.096/2 + 0.25 x 1.024 - 0.512 = 1.792V	 For V_{OUT}, use Equation 4 For V_{DIN}, use Table 1b first formula For G, use Table 2 For V_{OFFSET}, use Table 3 first formula

Numerical Examples

Several numerical examples for the MAX5318, as shown in <u>Table 7</u> and <u>Table 8</u>, illustrate how the gain and offset control changes the output voltage. The examples assume a reference voltage of 4.096V. Note that if the result of the calculation results in an under- or over-range output voltage, V_{OUT} is set to its zero or full-scale value, respectively. An under-range output is less than 0V and an over-range output is greater than V_{REF} - 1 LSB.

Reset

The device is reset upon power-on, hardware reset using \overline{RST} , or software reset using register 0x4, bit 15, command \overline{RSTSW} . After reset, the value of the input register, the DAC latch and the output voltage are set to the values defined by the M/\overline{Z} input. If a hardware reset occurs during a SPI programming frame, anything before and after the reset for the frame will be ignored. A software reset initiated through the SPI interface takes effect after the end of the valid frame.

Output State Upon Reset

The output voltage can be set to either zero or midscale upon power-up, or a hardware or software reset, depending on the state of the $M\overline{Z}$ input. After power-up, if the device detects that this input is low, the output voltage is set to zero scale. If $M\overline{Z}$ is high, the output voltage is set to midscale.

Note that during reset, when \overline{RST} is low or \overline{RSTSW} is set to 0, the output voltage is set slightly lower than the value after coming out of reset. During reset, the output voltage is set to the values shown for the $V_{OUT-RESET}$ specification in the *Electrical Characteristics*.

Power-Down

The device can be powered down by either hardware (pulling PD high) or software (setting the PD_SW bit in either the 0x4 or 0xC registers). Note that the hardware and software inputs are ORed. Asserting either is enough to place the device in power-down mode.

In order to restore normal operation to the device, satisfy both of these conditions:

- 1) Pull PD low.
- 2) Set the bits PD_SW's (in both 0x4 and 0xC registers) to 0.

In power-down, the output is internally connected to AGND through a $2k\Omega$ resistor. The SPI interface remains active and the DAC register content remains unchanged.

Data Format Selection (Straight Binary vs. Two's Complement)

The MAX5318 interprets the data code input (DIN) as either straight binary or two's complement. To choose the straight binary format, set the TC/SB input low. For two's complement, set the input high.

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LDAC and **BUSY** Interaction

The $\overline{\text{BUSY}}$ line is open drain and is normally pulled up by an external resistor. It is software-configurable bidirectional and can be pulled down externally. If any of the DIN, GAIN, and OFFSET registers is changed, the device must calculate the value to be presented to the DAC register. To indicate to the host processor that the device is busy, the device pulls the $\overline{\text{BUSY}}$ output low. Once computation is complete, the device releases $\overline{\text{BUSY}}$ and the host processor can load the DAC by toggling the $\overline{\text{LDAC}}$ input. If $\overline{\text{LDAC}}$ is set low while $\overline{\text{BUSY}}$ is low, the $\overline{\text{LDAC}}$ event is latched and implemented when the computation is complete and $\overline{\text{BUSY}}$ rises.

There are four ways in which the $\overline{\text{LDAC}}$ and $\overline{\text{BUSY}}$ outputs can be used. This is shown graphically in Figure 6.

- The host sends a new command. The device sets BUSY low. The host monitors BUSY to determine when it goes high. The device then pulses LDAC low to update the DAC.
- 2) The host sends a new command. The device sets BUSY low. The host toggles LDAC low then high before BUSY goes high. The device latches the LDAC

- event but does not implement it until processing is complete. Then, $\overline{\text{BUSY}}$ goes high and the device updates the DAC.
- 3) LDAC is held low. The host sends a new command and the device sets BUSY low. The device updates the DAC when the processing is complete and BUSY goes high.
- 4) BUSY is pulled down externally to delay DAC update. The BUSY pin is bidirectional. To use BUSY as an input, set the NO_BUSY bit to 1 using the 0x4 or 0xC command. When configured as an input, pulling BUSY low at least 50ns before the device releases the line delays DAC update. DAC update occurs only after BUSY is released and goes high. If used as an input, drive BUSY with an open-drain output with a pullup to VDDIO. The processing required for calculating the final DAC code is controlled by an internally generated clock. The clock frequency is not related to any external signals and the frequency is not precisely defined. Therefore, if the DAC must be updated at a precise time with the least amount of jitter, use option 1.

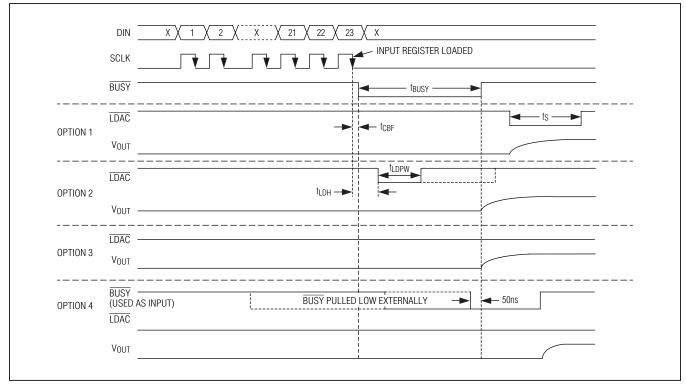


Figure 6. BUSY and LDAC Timing

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Serial Interface Overview

The SPI interface supports speeds up to 50MHz. When $\overline{\text{CS}}$ is high, the remaining interface inputs are disabled to reduce transient currents. The interface supports daisy chaining to enable multiple devices to be controlled on the same SPI bus.

The device has a double-buffered interface consisting of two register banks: the input register and the DAC register. The input register for DIN/GAIN/OFFSET is connected directly to the 24-bit SPI input shift register. The DAC latch contains the DAC code after digital processing and is loaded as defined in the \overline{LDAC} and \overline{BUSY} Interaction section above.

A valid SPI frame is 24-bit wide with 4-bit command R3 to R0, 18-bit data D17 to D0, and 2 unused LSBs. A full 24-bit SPI command sequence is required for all SPI command operations, regardless of the number of data bits actually used for the command. Any commands terminating with less than a full 24-bit sequence will be aborted without impacting the operation of the part (subject to t_{CSA} timing requirements). Data is not written into the SPI input register or DAC and it continues to hold the preceding valid data. If a command sequence with more than 24 bits is provided, the command will be executed on the 24th SCLK falling edge and the remainder of the command will be ignored.

All SPI commands result in the device assuming control of the DOUT line from the first SCLK edge through the 24th SCLK edge. After relinquishing the DOUT line, the MAX5318 returns to a high-impedance mode. An optional bus hold circuit can be engaged to hold DOUT at its last bit value while not interfering with other devices on the bus.

DOUT is disabled at power-up and must be enabled through the SPI interface. When enabled, DOUT echoes the 4-bit command plus 18-bit data, which is being programmed. During readback, DOUT echoes the 4-bit command followed by the true readback data depending

upon the type of read command. <u>Table 9</u> shows the bit positions for DOUT and DIN within the 24-bit SPI frame.

The device is designed such that SCLK idles low, and DIN and DOUT change on the rising clock edge and get latched on the falling clock edge. The SPI host controller should be set accordingly.

Daisy-Chain SPI Operation Using READY Output

The $\overline{\text{READY}}$ pulse appears 24 clock cycles after the negative edge of $\overline{\text{CS}}$ as shown in Figure 7 and can therefore be used as the $\overline{\text{CS}}$ line for the next device in the daisy chain. Since the device looks at the first 24 bits of the transmission following the falling edge of $\overline{\text{CS}}$, it is possible to daisy-chain the device with different command word lengths. $\overline{\text{READY}}$ goes high after $\overline{\text{CS}}$ is driven high.

To perform a daisy-chain write operation, drive $\overline{\text{CS}}$ low and output the data serially to DIN. The propagation of the $\overline{\text{READY}}$ signal then controls how the data is read by the device. As the data propagates through the daisy chain, each individual command in the chain is executed on the 24th falling clock edge following the falling edge of the respective $\overline{\text{CS}}$ input. To update just one device in a daisy chain, send the no-op command to the other device in the chain. To update the first device in the chain, raise the $\overline{\text{CS}}$ input after writing to that device.

Because daisy-chain operation requires paralleling the DOUTs of all the MAX5318 in the chain, the NO_HOLDEN bit in register 0x4 or 0xC should be set to 1 for all devices. Doing so ensures that DOUT goes into high-impedance after the SPI frame is complete (i.e. after the 24th clock cycle) as shown in Figure 8.

Stand-Alone Operation

The diagram in Figure 9 shows a stand-alone connection of the MAX5318 in a typical SPI application. If more than one peripheral device shares the DOUT bus, the NO_HOLDEN bit in register 0x4 or 0xC should be set to 1 for the MAX5318. Doing so ensures that DOUT goes into high-impedance after the SPI frame is complete (i.e. after the 24th clock cycle).

Table 9. SPI Command and Data Mapping with Clock Falling Edges

CLOCK EDGE	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24
DIN	R3	R2	R1	R0	D17	D16	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0	Χ	Χ
DOUT	0	R3	R2	R1	R0	D17	D16	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0	Χ

Note that 'X' is don't care.

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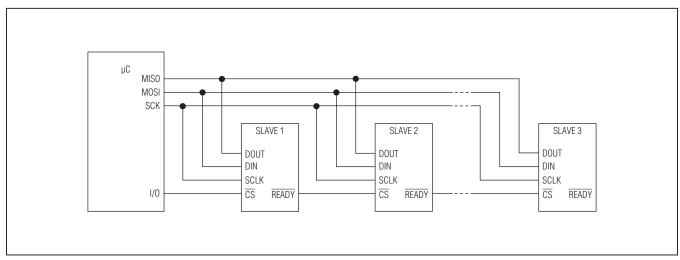


Figure 7. Daisy-Chain SPI Connection Terminating with a Standard SPI Device.

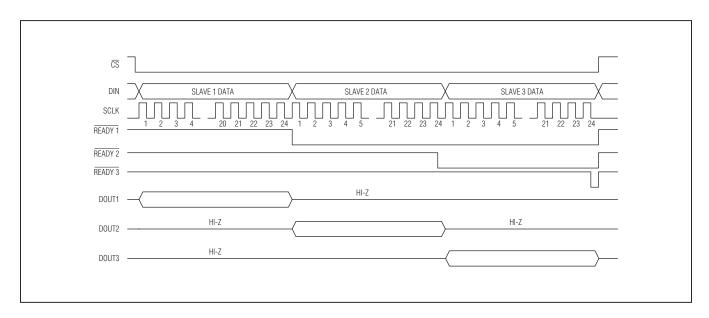


Figure 8. Daisy-Chain SPI Connection Timing

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Command and Register Map

All command and data registers have read and write functionality. The register selected depends on the command select bits R[3:0]. Each write to the device consists of 4 command select bits (R[3:0]), 18 data bits (which are detailed in Table 11 to Table 19), and 2 don't care LSBs. A summary of the commands is shown in Table 10.

Applications Information

Power-On Reset (POR)

Upon power-on, the output is set to either zero-scale (if M/\overline{Z} is low) and midscale (if M/\overline{Z} is high). The entire register map is set to their default values as shown in Table 11 to Table 19.

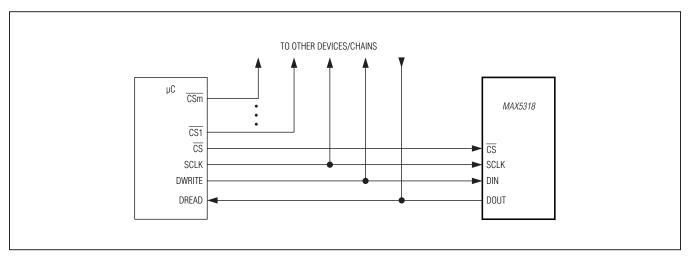


Figure 9. Stand-Alone Operation

Table 10. Register Map Summary

HEX	R3	R2	R1	R0	FUNCTION
0	0	0	0	0	No-op. Used mainly in daisy-chain communications.
1	0	0	0	1	DIN register write
2	0	0	1	0	OFFSET register write
3	0	0	1	1	GAIN register write
4	0	1	0	0	Configuration register write
5–8	_	_	_	_	Reserved
9	1	0	0	1	DIN register read
А	1	0	1	0	OFFSET register read
В	1	0	1	1	GAIN register read
С	1	1	0	0	Configuration and status register read.
D-F	_	_	_	_	Reserved

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Register Details

Table 11. No-Op Command (0x0)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	Χ	Χ	Χ	Х	Χ	Χ	Χ	Χ	Χ	Χ	Х	Х	Χ	Х	Х	Х	Χ	Х
DEFAULT	Χ	Χ	Χ	Х	Х	Χ	Х	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Х

BIT	NAME	DESCRIPTION
17:0	Don't care	No action on SPI shift register and DAC input registers. Use for daisy-chain purposes when R[3:0] = 0000.

Table 12a. Straight Binary DIN Write Register (TC/\overline{SB}) = 0) (0x1)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	B17	B16	B15	B14	B13	B12	B11	B10	B9	B8	B7	B6	B5	B4	ВЗ	B2	B1	B0
DEFAULT	0x000 0x200		en M/Z : en M/Z :															

BIT	NAME	DESCRIPTION
17:0	B[17:0]	18-bit DAC input code in straight binary format. For clarity, a few examples are shown below: 00 0000 0000 0000 0000 0000 0x00000 zero scale 01 0000 0000 0000 0000 0x10000 quarter scale 10 0000 0000 0000 0000 0x20000 midscale 11 0000 0000 0000 0000 0x30000 three-quarter scale 11 1111 1111 1111 0x3FFFF full scale - 1 LSB

Table 12b. Two's Complement DIN Write Register (TC/\overline{SB}) = 1) (0x1)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	B17	B16	B15	B14	B13	B12	B11	B10	В9	B8	В7	В6	B5	B4	ВЗ	B2	В1	В0
DEFAULT				= DG1 = V _{DD}														

BIT	NAME	DESCRIPTION
17:0	B[17:0]	18-bit DAC input code in two's complement format. For clarity, a few examples are shown below: 10 0000 0000 0000 0000 0x20000 zero scale 11 0000 0000 0000 0000 0x30000 quarter scale 11 1111 1111 1111 1111 0x3FFFF midscale - 1 LSB 00 0000 0000 0000 0000 0x00000 midscale 00 0000 0000 0000 0001 0x00001 midscale + 1 LSB 01 0000 0000 0000 0000 0x10000 three-quarter scale 01 1111 1111 1111 1111 0x1FFFF full scale - 1 LSB

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Table 13. OFFSET Register Write in Two's Complement (0x2)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	B17	B16	B15	B14	B13	B12	B11	B10	В9	B8	В7	В6	B5	В4	ВЗ	B2	B1	В0
DEFAULT	0x000	000—Ze	ero Offs	set														

BIT	NAME	DESCRIPTION
17:0	B[17:0]	18-bit offset code in two's complement format. For clarity, a few examples are shown below: 10 0000 0000 0000 0000 0000 0x20000 offset of -2 ¹⁷ 11 1111 1111 1111 1111 0x3FFFF offset of -1 00 0000 0000 0000 0000 0x00000 offset of 0 00 0000 0000 0000 0001 0x00001 offset of +1 01 1111 1111 1111 1111 0x1FFFF offset of 2 ¹⁷ – 1

Table 14. GAIN Write Register (0x3)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	B17	B16	B15	B14	B13	B12	B11	B10	B9	B8	B7	B6	B5	B4	ВЗ	B2	B1	B0
DEFAULT	0x3FF	FF—Ga	in of 1															

BIT	NAME		DESCRIPTION	
17:0	B[17:0]	18-bit gain code. For clarity, 11 1111 1111 1111 1111 11 1111 1111 1	les are shown below: Gain of 1. $(2^{18} - 1 + 1)/2^{18}$ Gain of 0.999996. $(2^{18} - 2 + 1)/2^{18}$ Gain of 0.5. $(2^{17} - 1 + 1)/2^{18}$ Gain of 0.499996. $(2^{17} - 2 + 1)/2^{18}$ Gain of 0.0000076. $1/2^{18}$	

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Table 15. General Configuration Write Register (0x4)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	PD_SW	NO_HOLDEN	RST_SW	NO_BUSY	DOUT_ON	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ
DEFAULT	0	0	1	0	0	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ	Χ

BIT	NAME	DESCRIPTION
17	PD_SW	Software PD (Power-Down). Equivalent to the PD input. 0: Normal mode 1: Power-down mode. OUT is internally connected to AGND using a $2k\Omega$ resistor.
16	NO_HOLDEN	SPI Bus Hold Enable. 0: Bus hold enabled for SPI DOUT output. DOUT stays at its last value after the SPI $\overline{\text{CS}}$ input rises at the end of the SPI frame (i.e. after the 24th clock cycle). 1: Bus hold disabled for SPI DOUT output. DOUT goes high impedance after the SPI $\overline{\text{CS}}$ input rises at the end of the SPI frame (i.e. after the 24th clock cycle).
15	RST_SW	Software Reset. Equivalent to the RST input. 0: Place device in reset 1: Normal operation Set the active low RST_SW bit low to initiate a software reset (equivalent to pulling RST low)
14	NO_BUSY	BUSY Input Disable. 0: BUSY input is active. 1: BUSY input is disabled. Note that this does not affect the BUSY bit in the General Configuration and Status Register. The BUSY pin is bidirectional. When enabled, it can be pulled down externally to delay DAC updates.
13	DOUT_ON	SPI DOUT Output Disable. DOUT is disabled by default. 0: DOUT output disabled. When DOUT is disabled, the output is pulled low for the duration of the SPI frame. 1: DOUT output enabled.
12:0	_	Don't care. These bits are reserved for the corresponding read command.

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Table 16. DIN Read Register (0x9)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	B17	B16	B15	B14	B13	B12	B11	B10	В9	B8	B7	B6	B5	B4	ВЗ	B2	B1	B0
DEFAULT	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

BIT	NAME	DESCRIPTION
17:0	B[17:0]	18-bit DIN readback value.

Table 17. OFFSET Read Register (0xA)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	B17	B16	B15	B14	B13	B12	B11	B10	В9	B8	В7	В6	B5	В4	ВЗ	B2	B1	В0
DEFAULT	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

BIT	NAME	DESCRIPTION
17:0	B[17:0]	18-bit OFFSET readback value in two's complement.

Table 18. GAIN Read Register (0xB)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	B17	B16	B15	B14	B13	B12	B11	B10	В9	B8	B7	B6	B5	B4	ВЗ	B2	B1	B0
DEFAULT	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1

BIT	NAME	DESCRIPTION
17:0	B[17:0]	18-bit GAIN readback value.

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Table 19. General Configuration and Status Read Register (0xC)

BIT	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
NAME	PD_SW	NO_ HOLDEN	RST_SW	NO_BUSY	DOUT_ON	BUSY	X	X	X	X	Х	X	RE	V_II	D[3:	0]	Χ	Х
DEFAULT	0	0	1	0	0	0	0	0	0	0	0	0		000	01		0	0

BIT	NAME	DESCRIPTION
17	PD_SW	Software PD (Power-Down). Equivalent to the PD input. 0: Normal mode. 1: Power-down mode. OUT is internally connected to AGND using a 2kΩ resistor.
16	NO_HOLDEN	SPI Bus Hold Enable. 0: Bus hold enabled for SPI DOUT output. DOUT stays at its final value after the SPI $\overline{\text{CS}}$ input rises at the end of the SPI frame. 1: Bus hold disabled for SPI DOUT output. DOUT goes high impedance after the SPI $\overline{\text{CS}}$ input rises at the end of the SPI frame.
15	RST_SW	Software Reset. Equivalent to the RST input. 0: Place device in reset. 1: Normal operation. Set the active low RST_SW bit low to initiate a software reset (equivalent to pulling RST low).
14	NO_BUSY	BUSY Input Disable. 0: BUSY input is active. 1: BUSY input is disabled. Note that this does not affect the BUSY bit in the General Configuration and Status Register. The BUSY pin is bidirectional. When enabled, it can be pulled down externally to delay DAC updates.
13	DOUT_ON	SPI DOUT Output Disable. DOUT is disabled by default. 0: DOUT output disabled. When DOUT is disabled, the output is pulled low for the duration of the SPI frame. 1: DOUT output enabled.
12	BUSY	Global BUSY status readback. 0: Device is busy calculating output voltage. 1: Device is not busy.
11:6	_	Reserved. Will read back 0.
5:2	REV_ID[3:0]	Device revision
1:0	_	Reserved. Will read back 0.

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Power Supplies and Bypassing Considerations

For best performance, use a separate supply for the MAX5318. Bypass VDDIO, AVDD_, and AVSS with high-quality ceramic capacitors to a low-impedance ground as close as possible to the device. A typical high-quality X5R 10µF capacitor can become self resonant at 2MHz. Therefore, it is actually an inductor above 2MHz and is useless for decoupling signals above 2MHz. It is therefore recommended that several capacitors of different values are connected in parallel. Figure 10 shows the magnitude of impedance of typical 1µF, 100nF, and 10nF X5R capacitors. As the capacitance reduces, the self-resonant frequency increases. In addition, the parallel combination of all three is shown and exhibits a significant improvement over a single capacitor. These plots do not include any PCB trace inductance.

Minimize lead lengths to reduce lead inductance. Adding just 2nH trace inductance to each of the typical capacitors above produces the effects shown in Figure 11. This shows significant reduction in the self-resonant frequencies of the capacitors.

Internal Linear Regulator (BYPASS)

BYPASS is the output of an internal linear regulator and is used to power digital circuitry. Connect BYPASS to DGND with a ceramic capacitor in the range of $1\mu F$ to $10\mu F$ with ESR in the range of $100m\Omega$ to $20m\Omega$ to ensure stability. The typical voltage on this pin is 2.4V. Use a low-leakage capacitor to ensure low power-down current.

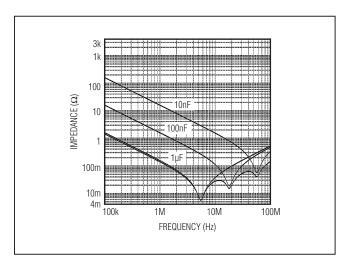


Figure 10. Typical X5R Capacitor Impedance

Power-Supply Sequencing

During power-up, ensure that AVDD_ comes up before the reference does. If this is not possible, connect a Schottky diode between the REF and AVDD_ such as the MBR0530T1G. If REF does come up before AVDD_, the diode conducts and clamps REF to AVDD_. Once AVDD_ has come up, the diode no longer conducts. REF should always be below AVDD_ as specified in the *Electrical Characteristics*. AVDD_ and AVDD_ should be connected together and powered from the same supply.

VDDIO and AVSS can be sequenced in any order. Always perform a reset operation after all the supplies are brought up to place the device in a known operating state.

Layout Considerations

Digital and AC transient signals on AGND inputs can create noise at the outputs. Connect both AGND inputs to form the star ground for the DAC system. Refer remote DAC loads to this system ground for the best possible performance (see the *Force/Sense* section).

Use proper grounding techniques, such as a multilayer board with a low-inductance ground plane, or star connect all ground return paths back to AGND. Do not use wire-wrapped boards and sockets. Use ground plane shielding to improve noise immunity. Do not run analog and digital signals parallel to one another (especially clock signals) and avoid routing digital lines underneath the device package.

For a recommended layout, consult the MAX5318 Evaluation Kit datasheet.

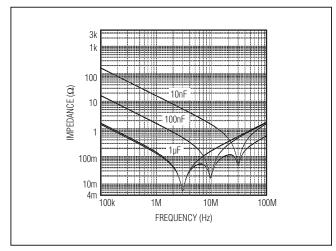


Figure 11. Typical X5R Capacitor Impedance with Additional 2nH PCB Trace Inductance

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Voltage Reference Selection and Layout

The voltage reference should be placed close to the DAC. The same power-supply decoupling and grounding rules as the DAC should be implemented. Many voltage references require an output capacitor for stability or noise reduction. Provided the trace between the reference device and the DAC is kept short and well shielded, a single capacitor may be used and placed close to the DAC. However, for improved noise immunity, additional capacitors may be used but be careful not to exceed the recommended capacitance range for the voltage reference.

Refer to Maxim Applications Note AN4300: Calculating the Error Budget in Precision Digital-to-Analog Converter (DAC) Applications for detailed description of voltage reference parameters and trading off the error budget. The MAX6126 is recommended for use with this device.

Optimizing Data Throughput Rate

The \(\overline{LDAC}\) and \(\overline{BUSY}\) Interaction section details the timing of data written to the device and how the DAC is updated. Data throughput speed can be increased by overlapping the data load time with the calibration and settling time as shown below in \(\overline{Figure 12}\). Following the 24th SCLK falling edge, the device starts its calibration period. Providing that the \(\overline{LDAC}\) falling edge arrives before the 24th SCLK falling edge, and assuming the SPI clock frequency is high enough, the throughput period is therefore limited by the internal calculation and settling times only. A slight further increase in throughput time can be gained by either toggling \(\overline{LDAC}\) during the calculation time or by pulling it low permanently. However,

the exact point at which the DAC update occurs is then determined internally as indicated by the BUSY line rising edge. This is not an exact time.

BUSY Line Pullup Resistor Selection

The $\overline{\text{BUSY}}$ pin is an open-drain output. It therefore requires a pullup resistor. $2\text{k}\Omega$ value is recommended as a compromise between power and speed. Stray capacitance on this line can easily slow the rise time to an unacceptable level. The $\overline{\text{BUSY}}$ pin can sink up to 5mA. Therefore a resistor as low as $V_{DDIO}/0.005$ may be used if faster rise times are required.

Producing Unipolar High-Voltage and Bipolar Outputs

Figure 11 and Figure 12 show how external op amps can be used to produce a unipolar high-voltage output and a bipolar output

Definitions

Integral Nonlinearity (INL)

INL is the deviation of the measured transfer function from a straight line drawn between two codes. This line is drawn between the zero and full-scale codes of the transfer function, once offset and gain errors have been nullified.

Differential Nonlinearity (DNL)

DNL is the difference between an actual step height and the ideal value of 1 LSB. If the magnitude of the DNL is less than or equal to 1 LSB, the DAC guarantees no missing codes and is monotonic.

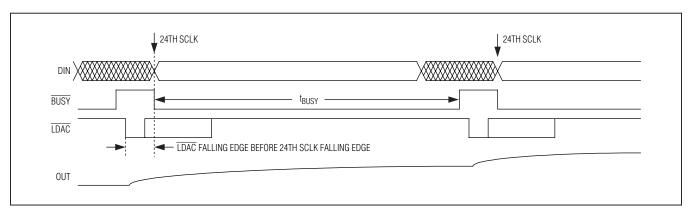


Figure 12. Optimum Throughput with Stable Update Period

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Offset Error

Offset error indicates how well the actual transfer function matches the ideal transfer function at a single point. Typically, the point at which the offset error is specified is at or near the zero-scale point of the transfer function.

Gain Error

Gain error is the difference between the ideal and the actual full-scale output voltage on the transfer curve, after nullifying the offset error. This error alters the slope of the transfer function and corresponds to the same percentage error in each step.

Settling Time

The settling time is the amount of time required from the start of a LDAC high-to-low transition or BUSY low-to-high transition (whichever occurs last), until the DAC output settles to within 0.003% of the final value.

Digital Feedthrough

Digital feedthrough is the amount of noise that appears on the DAC output when the DAC digital control lines are toggled.

Digital-to-Analog Glitch Impulse

The glitch impulse occurs at the major carry transitions along the segmented bit boundaries. It is specified as the net area of the glitch impulse which appears at the output when the digital input code changes by 1 LSB. The glitch impulse is specified in nanovolts-seconds (nV-s).

Digital-to-Analog Power-Up Glitch Impulse

The digital-to-analog power-up glitch is the net area of the glitch impulse which appears at the output when the device exits power-down mode.

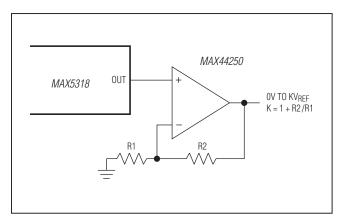


Figure 13. Unipolar High-Voltage Output

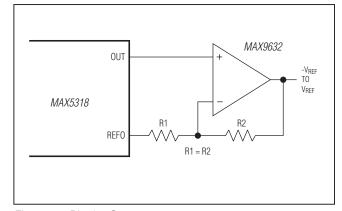
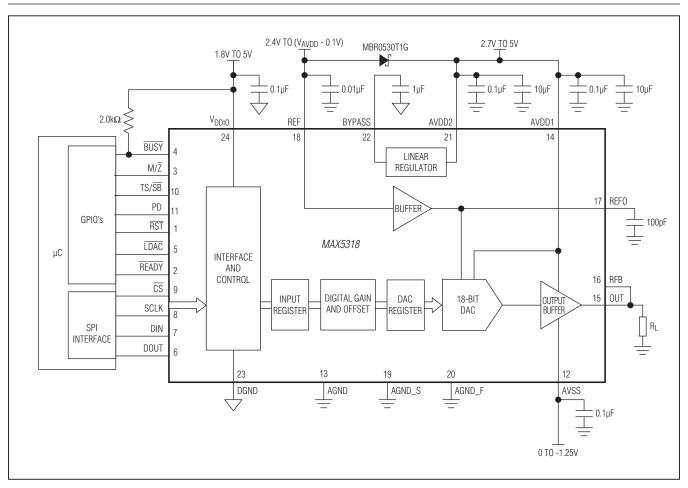


Figure 14. Bipolar Output

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Typical Operating Circuit



Ordering Information

PART	TEMP RANGE	PIN-PACKAGE
MAX5318GUG+	-40°C to +105°C	24 TSSOP

⁺Denotes a lead(Pb)-free/RoHS-compliant package.

Chip Information

PROCESS: BiCMOS

Package Information

For the latest package outline information and land patterns (footprints), go to www.maximintegrated.com/packages. Note that a "+", "#", or "-" in the package code indicates RoHS status only. Package drawings may show a different suffix character, but the drawing pertains to the package regardless of RoHS status.

PACKAGE	PACKAGE	OUTLINE	LAND
TYPE	CODE	NO.	PATTERN NO.
24 TSSOP	U24+1	<u>21-0066</u>	<u>90-0118</u>

18-Bit, High-Accuracy Voltage Output DAC with Digital Gain, Offset Control, and SPI Interface

Revision History

REVISION	REVISION	DESCRIPTION	PAGES
NUMBER	DATE		CHANGED
0	9/12	Initial release	



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OOO «ЛайфЭлектроникс" "LifeElectronics" LLC

ИНН 7805602321 КПП 780501001 P/C 40702810122510004610 ФАКБ "АБСОЛЮТ БАНК" (ЗАО) в г.Санкт-Петербурге К/С 3010181090000000703 БИК 044030703

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- Техническую поддержку проекта.
- Защиту от снятия компонента с производства.
- Оценку стоимости проекта по компонентам.
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Тел: +7 (812) 336 43 04 (многоканальный) Email: org@lifeelectronics.ru